

AMC23C11 Fast Response, Reinforced Isolated Comparator With Adjustable Threshold and Latch Function

1 Features

- Wide high-side supply range: 3V to 27V
- Low-side supply range: 2.7V to 5.5V
- Adjustable threshold: 20mV to 2.7V
- Reference current for threshold adjustment:
 - 100µA, ±1%
- Trip threshold error: ±1% (max) at 250mV
- Open-drain output with optional latch mode
- Propagation delay: 240ns (typ)
- High CMTI: 75V/ns (min)
- Safety-related certifications:
 - 7000V_{PK} reinforced isolation per DIN EN IEC 60747-17 (VDE 0884-17)
 - 5000V_{RMS} isolation for 1 minute per UL1577
- Fully specified over the extended industrial temperature range: -40°C to +125°C

2 Applications

- Overcurrent or overvoltage detection in:
 - Motor drives
 - Frequency inverters
 - Solar inverters
 - DC/DC converters

3 Description

The AMC23C11 is an isolated comparator with a short response time. The open-drain output is separated from the input circuitry by an isolation barrier that is highly resistant to magnetic interference. This barrier is certified to provide reinforced galvanic isolation of up to 5kV_{RMS} according to VDE 0884-17 and UL1577, and supports a working voltage of up to 1kV_{RMS}.

The trip threshold is adjustable from 20mV to 450mV in low-hysteresis mode and from 600mV to 2.7V in high-hysteresis mode through a single external resistor.

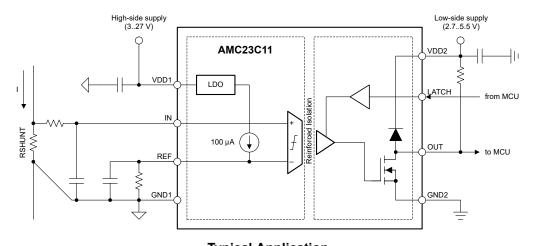
The open-drain output on the device supports transparent mode (LATCH input tied to GND2) where the output follows the input state, or latch mode, where the output is cleared on the falling edge of the latch input signal.

The AMC23C11 is available in an 8-pin, wide-body SOIC package and is specified over the extended industrial temperature range of -40°C to +125°C.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
AMC23C11	DWV (SOIC, 8)	5.85mm × 11.5mm

- For all available packages, see the orderable addendum at the end of the data sheet.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Typical Application



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4 Pin Configuration and Functions

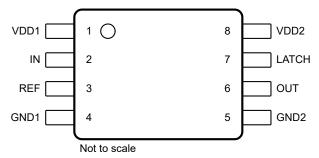


Figure 4-1. DWV Package, 8-Pin SOIC (Top View)

Table 4-1. Pin Functions

	PIN	TYPE	DESCRIPTION
NO.	NAME	IIFE	DESCRIPTION
1	VDD1	High-side power	High-side power supply ⁽¹⁾
2	IN	Analog input	Analog input pin to the comparator
3	REF	Analog input	Reference pin that defines the trip threshold. The voltage on this pin also affects the hysteresis of the comparator, as explained in the <i>Reference Input</i> section. This pin is internally connected to a 100µA current source. Connect a resistor from REF to GND1 to define the trip threshold, and a capacitor from REF to GND1 to filter the reference voltage. For best transient noise immunity, place the capacitor as closely to the pin as possible. This pin can also be driven by an external voltage source.
4	GND1	High-side ground	High-side ground
5	GND2	Low-side ground	Low-side ground
6	OUT	Digital output	Open-drain output of the comparator. Connect to an external pullup resistor.
7	LATCH	Digital input	Digital input to select latch mode (high) or transparent mode (low) of the open-drain output. Do not leave the input pin unconnected (floating). Connect to GND2 when not used.
8	VDD2	Low-side power	Low-side power supply ⁽¹⁾

⁽¹⁾ See the *Power Supply Recommendations* section for power-supply decoupling recommendations.



5 Specifications

5.1 Absolute Maximum Ratings

see(1)

		MIN	MAX	UNIT
Power-supply voltage	VDD1 to GND1	-0.3	30	V
Fower-supply voltage	VDD2 to GND2	-0.3	6.5	v
Analog input voltage	REF to GND1	-0.5	6.5	V
Analog input voltage	IN to GND1	-6	5.5	v
Digital input voltage	LATCH to GND2	-0.5	VDD2 + 0.5	V
Digital output voltage	OUT to GND2	-0.5	VDD2 + 0.5	V
Input current	Continuous, any pin except power-supply pins	-10	10	mA
Temperature	Junction, T _J		150	°C
Temperature	Storage, T _{stg}	-65	150	O

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
V _(ESD)	Liectrostatic discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1000	·

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

Product Folder Links: AMC23C11



5.3 Recommended Operating Conditions

over operating ambient temperature range (unless otherwise noted)

·		,	MIN	NOM	MAX	UNIT
POWER	R SUPPLY					
V _{VDD1}	High-side power-supply voltage	VDD1 to GND1	3.0	5	27	V
V _{VDD2}	Low-side power supply voltage	VDD2 to GND2	2.7	3.3	5.5	V
ANALO	OG INPUT		1			
V	Innut valtage	IN to GND1, VDD1 ≤ 4.3 V	-0.4	VD	D1 – 0.3	V
V _{IN}	Input voltage	IN to GND1, VDD1 > 4.3 V	-0.4		4	V
\ /	Defenence welleng	Low hysteresis mode	20(2)		450	mV
V_{REF}	Reference voltage	High hysteresis mode	600		2700 ⁽¹⁾	
	Reference voltage headroom	VDD1 – V _{REF}	1.4			V
	Filter capacitance on REF pin		20	100		nF
DIGITA	L I/O		<u>'</u>			
	Digital input voltage	LATCH pin	GND2		VDD2	V
	Digital output voltage	OUT to GND2	GND2		VDD2	V
	Sink current	OUT	0		4	mA
TEMPE	RATURE RANGE	,	1			
T _A	Specified ambient temperature		-40	25	125	°C

5.4 Thermal Information

	THERMAL METRIC(1)	DWV (SOIC)	UNIT
	THERMAL WETRICY	8 PINS	ONII
$R_{\theta JA}$	Junction-to-ambient thermal resistance	102.8	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	45.1	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	63.0	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	14.3	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	61.1	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application

5.5 Power Ratings

	PARAMETER	TEST CONDITIONS	VALUE	UNIT
		VDD1 = 25 V, VDD2 = 5.5 V	95	
P _D	Maximum power dissipation (both sides)	VDD1 = VDD2 = 5.5 V	30	mW
		VDD1 = VDD2 = 3.6 V	20	
		VDD1 = 25 V	83	
P _{D1}	Maximum power dissipation (high-side)	VDD1 = 5.5 V	18	mW
		VDD1 = 3.6 V	12	
D	Maximum power discipation (low side)	VDD2 = 5.5 V	12	mW
P _{D2}	Maximum power dissipation (low-side)	VDD2 = 3.6 V	8	IIIVV

Product Folder Links: AMC23C11

Reference voltages (V_{REF}) >1.6V require V_{VDD1} > $V_{VDD1,MIN}$ to maintain minimum headroom ($V_{VDD1} - V_{REF}$) of 1.4V. The device has been tested with V_{REF} as low as 5mV. The device remains functional but relative switching threshold accuracy can (2) decrease because of offset errors.



5.6 Insulation Specifications (Reinforced Isolation)

over operating ambient temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	VALUE	UNIT
GENER	AL			
CLR	External clearance ⁽¹⁾	Shortest pin-to-pin distance through air	≥ 8.5	mm
CPG	External creepage ⁽¹⁾	Shortest pin-to-pin distance across the package surface	≥ 8.5	mm
DTI	Distance through insulation	Minimum internal gap (internal clearance) of the double insulation	≥ 15.4	μm
СТІ	Comparative tracking index	DIN EN 60112 (VDE 0303-11); IEC 60112	≥ 600	V
	Material group	According to IEC 60664-1	1	
	Overvoltage category	Rated mains voltage ≤ 600V _{RMS}	1-111	
	per IEC 60664-1	Rated mains voltage ≤ 1000V _{RMS}	1-11	
DIN EN	IEC 60747-17 (VDE 0884-17) (2)			
V _{IORM}	Maximum repetitive peak isolation voltage	At AC voltage	1410	V _{PK}
V	Maximum-rated isolation	At AC voltage (sine wave)	1000	V _{RMS}
V_{IOWM}	working voltage	At DC voltage	1410	V_{DC}
V _{IOTM}	Maximum transient isolation voltage	$V_{TEST} = V_{IOTM}$, t = 60s (qualification test), $V_{TEST} = 1.2 \times V_{IOTM}$, t = 1s (100% production test)	7070	V _{PK}
V _{IMP}	Maximum impulse voltage ⁽³⁾	Tested in air, 1.2/50µs waveform per IEC 62368-1	7700	V _{PK}
V _{IOSM}	Maximum surge isolation voltage ⁽⁴⁾	Tested in oil (qualification test), 1.2/50µs waveform per IEC 62368-1	10000	V _{PK}
		Method a, after input/output safety test subgroups 2 and 3, $V_{pd(ini)} = V_{IOTM}, t_{ini} = 60s, V_{pd(m)} = 1.2 \times V_{IORM}, t_{m} = 10s$	≤ 5	
a	Apparent charge ⁽⁵⁾	Method a, after environmental tests subgroup 1, $V_{pd(ini)} = V_{IOTM}$, $t_{ini} = 60s$, $V_{pd(m)} = 1.6 \times V_{IORM}$, $t_m = 10s$	≤ 5	
q _{pd}	Apparent charge.	Method b1, at preconditioning (type test) and routine test, $V_{pd(ini)} = 1.2 \times V_{IOTM}$, $t_{ini} = 1$ s, $V_{pd(m)} = 1.875 \times V_{IORM}$, $t_m = 1$ s	≤ 5	— pC
		Method b2, at routine test (100% production) ⁽⁷⁾ $V_{pd(ini)} = V_{pd(m)} = 1.2 \times V_{IOTM}, t_{ini} = t_m = 1s$	≤ 5	
C _{IO}	Barrier capacitance, input to output ⁽⁶⁾	V _{IO} = 0.5 V _{PP} at 1MHz	≅ 1.5	pF
		V _{IO} = 500V at T _A = 25°C	> 10 ¹²	
R _{IO}	Insulation resistance, input to output ⁽⁶⁾	V _{IO} = 500V at 100°C ≤ T _A ≤ 125°C	> 10 ¹¹	Ω
		V _{IO} = 500V at T _S = 150°C	> 10 ⁹	
	Pollution degree		2	
	Climatic category		55/125/21	
UL1577	•			'
V _{ISO}	Withstand isolation voltage	$V_{TEST} = V_{ISO}$, t = 60s (qualification test), $V_{TEST} = 1.2 \times V_{ISO}$, t = 1s (100% production test)	5000	V _{RMS}

- (1) Apply creepage and clearance requirements according to the specific equipment isolation standards of an application. Care must be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board (PCB) do not reduce this distance. Creepage and clearance on a PCB become equal in certain cases. Techniques such as inserting grooves, ribs, or both on a PCB are used to help increase these specifications.
- (2) This coupler is suitable for *safe electrical insulation* only within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.
- (3) Testing is carried out in air to determine the surge immunity of the package.
- (4) Testing is carried in oil to determine the intrinsic surge immunity of the isolation barrier.
- (5) Apparent charge is electrical discharge caused by a partial discharge (pd).
- (6) All pins on each side of the barrier are tied together, creating a two-pin device.
- (7) Either method b1 or b2 is used in production.

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5.7 Safety-Related Certifications

VDE	UL
DIN EN IEC 60747-17 (VDE 0884-17), EN IEC 60747-17, DIN EN IEC 62368-1 (VDE 0868-1), EN IEC 62368-1, IEC 62368-1 Clause: 5.4.3; 5.4.4.4; 5.4.9	Recognized under 1577 component recognition and CSA component acceptance NO 5 programs
Reinforced insulation	Single protection
Certificate number: 40040142	File number: E181974

5.8 Safety Limiting Values

Safety limiting⁽¹⁾ intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the I/O can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Sofaty input, output, or output, ourrent	R _{θJA} = 102.8°C/W, VDD1 = VDD2 = 5.5 V, T _J = 150°C, T _A = 25°C			220	mA
Is	Safety input, output, or supply current	R _{θJA} = 102.8°C/W, VDD1 = VDD2 = 3.6 V, T _J = 150°C, T _A = 25°C			340	IIIA
Ps	Safety input, output, or total power	R _{θJA} = 102.8°C/W, T _J = 150°C, T _A = 25°C			1220	mW
Ts	Maximum safety temperature				150	°C

The maximum safety temperature, T_S , has the same value as the maximum junction temperature, T_J , specified for the device. The I_S and P_S parameters represent the safety current and safety power, respectively. Do not exceed the maximum limits of I_S and P_S. These limits vary with the ambient temperature, T_A.

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The junction-to-air thermal resistance, $R_{\theta JA}$, in the *Thermal Information* table is that of a device installed on a high-K test board for leaded surface-mount packages. Use these equations to calculate the value for each parameter:

 $T_J = T_A + R_{\theta JA} \times P$, where P is the power dissipated in the device.

 $T_{J(max)} = T_S = T_A + R_{\theta JA} \times P_S, \text{ where } T_{J(max)} \text{ is the maximum junction temperature.}$ $P_S = I_S \times \text{AVDD}_{max} + I_S \times \text{DVDD}_{max}, \text{ where AVDD}_{max} \text{ is the maximum high-side voltage and DVDD}_{max} \text{ is the maximum controller-side}$ supply voltage.



5.9 Electrical Characteristics

minimum and maximum specifications apply from T_A = -40°C to 125°C, VDD1 = 3.0 V to 27 V, VDD2 = 2.7 V to 5.5 V, V_{REF} = 20 mV to 2.7 V⁽¹⁾, and V_{IN} = -400 mV to 4 V⁽³⁾; typical specifications are at T_A = 25°C, VDD1 = 5 V, VDD2 = 3.3 V, and V_{REF} = 250 mV (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
ANALOG	G INPUT	,				
R _{IN}	Input resistance	IN pin, 0 ≤ V _{IN} ≤ 4 V		1		GΩ
		IN pin, $0 \le V_{IN} \le 4 V^{(3)}$		0.1	25	
I _{BIAS}	Input bias current	IN pin, $-400 \text{ mV} \le V_{IN} \le 0 \text{ V}^{(4)}$	-310	-0.5		nA
C _{IN}	Input capacitance	IN pin		4		pF
REFERE	NCE PIN					
I _{REF}	Reference current	REF to GND1, 20 mV < V _{REF} ≤ 2.7 V	99	100	101	μA
	Made coloction threshold	V _{REF} rising	500	550	600	ma\/
V _{MSEL}	Mode selection threshold	V _{REF} falling	450	500	550	mV
	Mode selection threshold hysteresis			50		mV
COMPA	RATOR					-
V _{IT+}	Positive-going trip threshold		V _{RI}	F + V _{HYS}		mV
		$(V_{IT+} - V_{REF} - V_{HYS}),$ $V_{REF} = 20 \text{ mV}, V_{HYS} = 4 \text{ mV}$	-2		2	
E _{IT+}	Positive-going trip threshold error	$ \begin{aligned} &(V_{\text{IT+}} - V_{\text{REF}} - V_{\text{HYS}}), \\ &V_{\text{REF}} = 250 \text{ mV}, V_{\text{HYS}} = 4 \text{ mV} \end{aligned} $	-2		2	mV
		$(V_{IT+} - V_{REF} - V_{HYS}),$ $V_{REF} = 2 V, V_{HYS} = 25 \text{ mV}$	-5		5	
V _{IT} _	Negative-going trip threshold			V _{REF}		mV
		$(V_{IT-} - V_{REF})$, $V_{REF} = 20 \text{ mV}$	-2.5		2.5	
E _{IT} _	Negative-going trip threshold error	$(V_{IT-} - V_{REF})$, $V_{REF} = 250 \text{ mV}$	-2.5		2.5	mV
		$(V_{IT-} - V_{REF})$, $V_{REF} = 2 V$	-5		5	
V	Trip throughold bystorogic	$(V_{IT+} - V_{IT-}), V_{REF} \le 450 \text{ mV}$		4		mV
V _{HYS}	Trip threshold hysteresis	$(V_{IT+} - V_{IT-})$, $V_{REF} \ge 600 \text{ mV}$		25		IIIV
DIGITAL	. I/O		·			
V _{IH}	High-level input voltage	LATCH pin	0.7 x VDD2		VDD2 + 0.3	V
V _{IL}	Low-level input voltage	LATCH pin	-0.3		0.3 x VDD2	V
C _{IN}	Input capacitance	LATCH pin		4		pF
V _{OL}	Low-level output voltage	I _{SINK} = 4 mA		80	250	mV
I _{LKG}	Open-drain output leakage current	VDD2 = 5 V, V _{OUT} = 5 V		5	100	nA
CMTI	Common-mode transient immunity	$ V_{IN} - V_{REF} \ge 4 \text{ mV}, R_{PULLUP} = 10 \text{ k}\Omega$	75	150		V/ns

Product Folder Links: AMC23C11

5.9 Electrical Characteristics (continued)

minimum and maximum specifications apply from T_A = -40°C to 125°C, VDD1 = 3.0 V to 27 V, VDD2 = 2.7 V to 5.5 V, V_{REF} = 20 mV to 2.7 V⁽¹⁾, and V_{IN} = -400 mV to 4 V⁽³⁾; typical specifications are at T_A = 25°C, VDD1 = 5 V, VDD2 = 3.3 V, and V_{REF} = 250 mV (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT					
POWER SU	OWER SUPPLY										
VDD1	VDD1 undervoltage detection threshold	VDD1 rising			3						
VDD1 _{UV}	Tundervoltage detection threshold	VDD1 falling			2.9	V					
VDD1 _{POR}	VDD1 power-on reset threshold	VDD1 falling			2.3	V					
VDD2	VDD2 undervoltege detection threshold	VDD2 rising			2.7	V					
VDD2 _{UV}	VDD2 undervoltage detection threshold	VDD2 falling			2.1	V					
I _{DD1}	High-side supply current			2.7	3.7	mA					
I _{DD2}	Low-side supply current			1.8	2.2	mA					

- (1) Reference voltages >1.6 V require VDD1 > VDD1_{MIN}. See the *Recommended Opertion Conditions* table for details.
- (2) But not exceeding the maximum input voltage specified in the Recommended Opertion Conditions table.
- (3) The typical value is measured at $V_{IN} = 0.4 \text{ V}$.
- (4) The typical value is measured at $V_{IN} = -400 \text{ mV}$.

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5.10 Switching Characteristics

over operating ambient temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT					
LATCH INPUT											
	Deglitch time	Falling edge	1.8		3.2	μs					
OPEN-	DRAIN OUTPUT		1		<u> </u>						
•	Propagation delay time IV I riging	VDD2 = 3.3 V, V _{REF} = 250 mV, V _{OVERDRIVE} = 10 mV, C _L = 15 pF		240	380	no					
t _{pH}	Propagation delay time, V _{IN} rising	VDD2 = 3.3 V, V _{REF} = 2 V, V _{OVERDRIVE} = 50 mV, C _L = 15 pF		210	340	ns					
4	Propagation delay time, V _{IN} falling	VDD2 = 3.3 V, V _{REF} = 250 mV, V _{OVERDRIVE} = 10 mV, C _L = 15 pF		240	380	no					
t _{pL}		VDD2 = 3.3 V, V _{REF} = 2 V, V _{OVERDRIVE} = 50 mV, C _L = 15 pF		340	ns						
t _f	Output signal fall time	$R_{PULLUP} = 4.7 \text{ k}\Omega, C_L = 15 \text{ pF}$		2		ns					
MODE S	SELECTION		_								
t _{HSEL}	Comparator hysteresis selection deglitch time	V _{REF} rising or falling		10		μs					
t _{DIS13}	Comparator disable deglitch time	V _{REF} rising		10		μs					
t _{EN13}	Comparator enable deglitch time	V _{REF} falling		100		μs					
START-	UP TIMING				'						
t _{LS ,STA}	Low-side start-up time	VDD2 step to 2.7 V, VDD1 ≥ 3.0 V		40		μs					
t _{HS ,STA}	High-side start-up time	VDD1 step to 3.0 V, VDD2 ≥ 2.7 V		45		μs					
t _{HS,BLK}	High-side blanking time			200		μs					
t _{HS,FLT}	High-side-fault detection delay time			100		μs					

5.11 Timing Diagrams

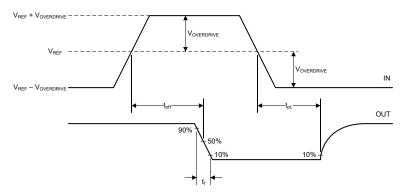


Figure 5-1. Rise, Fall, and Delay Time Definition (LATCH = Low)

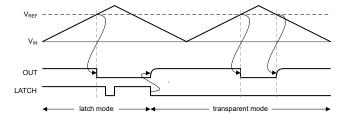
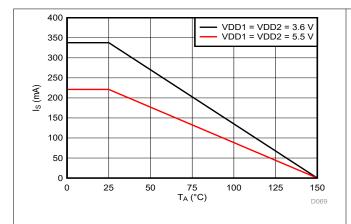


Figure 5-2. Functional Timing Diagram

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5.12 Insulation Characteristics Curves



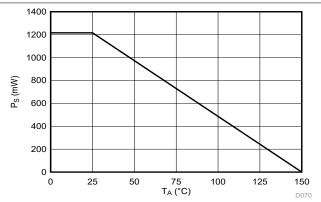
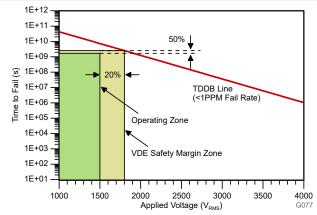


Figure 5-3. Thermal Derating Curve for Safety-Limiting Current per VDE

Figure 5-4. Thermal Derating Curve for Safety-Limiting Power per VDE

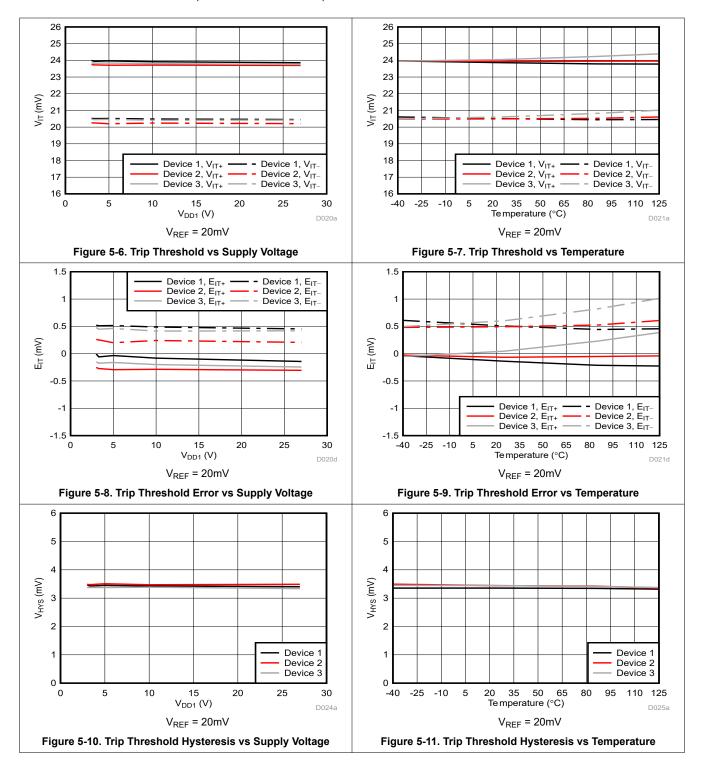


 T_A up to 150°C, stress-voltage frequency = 60Hz, isolation working voltage = 1000 V_{RMS} , operating lifetime > 400 years

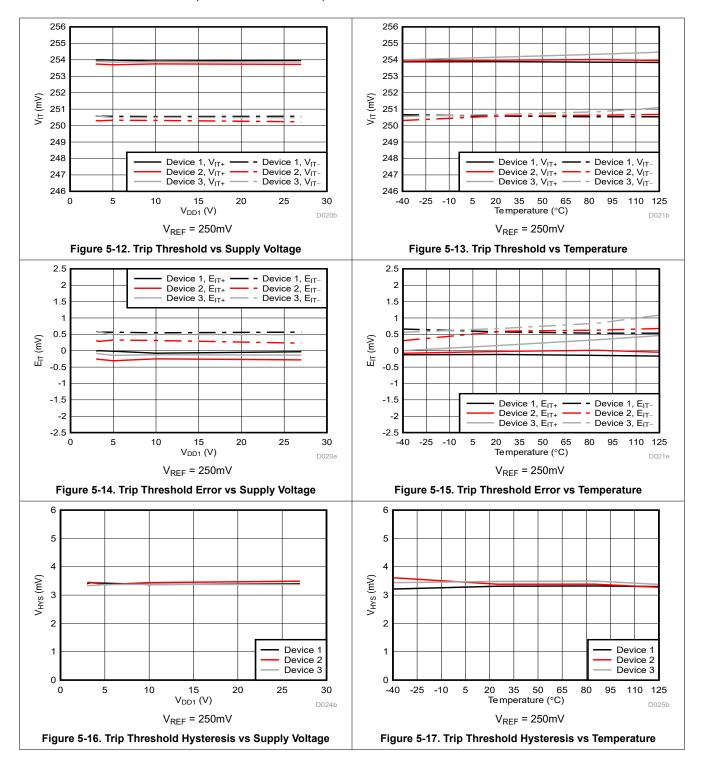


5.13 Typical Characteristics

At VDD1 = 5V and VDD2 = 3.3V (unless otherwise noted)

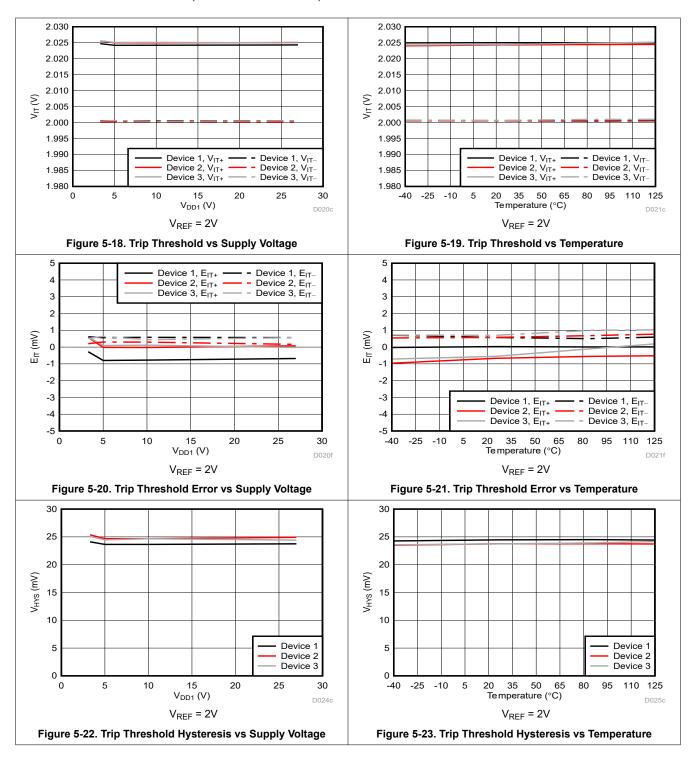


At VDD1 = 5V and VDD2 = 3.3V (unless otherwise noted)



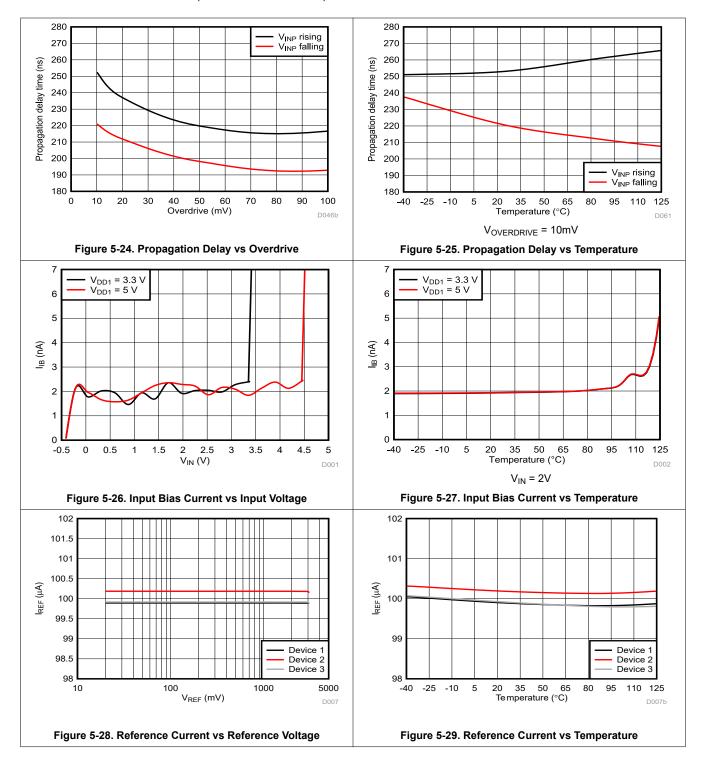


At VDD1 = 5V and VDD2 = 3.3V (unless otherwise noted)



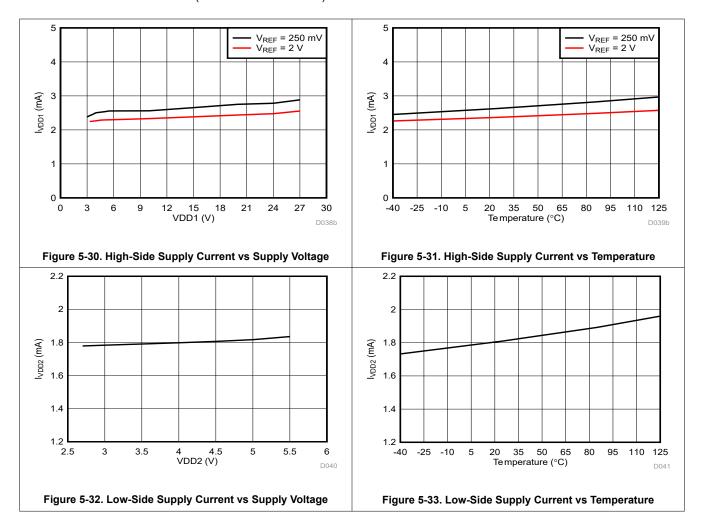
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At VDD1 = 5V and VDD2 = 3.3V (unless otherwise noted)





At VDD1 = 5V and VDD2 = 3.3V (unless otherwise noted)



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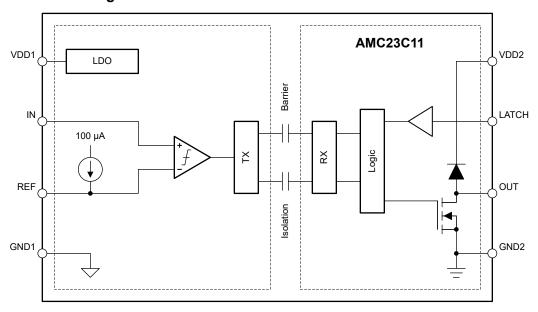
6 Detailed Description

6.1 Overview

The AMC23C11 is an isolated comparator with an open-drain output and optional latch function. The comparator compares the input voltage (V_{IN}) against the V_{IT+} threshold that is adjustable from 20mV to 2.7V through an internally generated 100µA reference current and a single external resistor. The open-drain output is actively pulled low when the input voltage (V_{IN}) is higher than the reference value V_{REF} . The behavior when V_{IN} drops below the trip threshold is determined by the LATCH pin, as described in the *Open-Drain Digital Output* section.

Galvanic isolation between the high- and low-voltage side of the device is achieved by transmitting the comparator states across a SiO₂-based, reinforced capacitive isolation barrier. This isolation barrier supports a high level of magnetic field immunity, as described in the *ISO72x Digital Isolator Magnetic-Field Immunity* application note. The digital modulation scheme used in the AMC23C11 to transmit data across the isolation barrier, and the isolation barrier characteristics, result in high reliability and common-mode transient immunity.

6.2 Functional Block Diagram



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6.3 Feature Description

6.3.1 Analog Input

The comparator trips when the input voltage (V_{IN}) rises above the V_{IT+} threshold that is defined as the reference value plus the internal hysteresis voltage. The comparator releases when V_{IN} drops below the V_{IT-} threshold that equals the reference value.

The difference between $V_{\text{IT+}}$ and $V_{\text{IT-}}$ is referred to as the *comparator hysteresis* and is 4mV for reference voltages below 450mV. The integrated hysteresis makes the AMC23C11 less sensitive to input noise and provides stable operation in noisy environments without having to add external positive feedback to create hysteresis. The hysteresis increases to 25mV for reference values (V_{REF}) greater than 600mV. See the *Reference Input* description for more details.

Figure 6-1 shows a timing diagram of the relationship between hysteresis and switching thresholds.

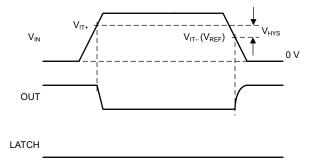


Figure 6-1. Switching Thresholds and Hysteresis

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6.3.2 Reference Input

The voltage on the REF pin determines the trip threshold of the comparator. The internal precision current source forces a $100\mu\text{A}$ current through an external resistor connected from the REF pin to GND1. The resulting voltage across the resistor (V_{REF}) equals the trip threshold, see Figure 6-1. Place a $100\mu\text{A}$ current source during power-up and the charging time can exceed the high-side blanking time ($t_{HS,BLK}$). In this case, as shown in Figure 6-2, the comparator can output an incorrect state after the high-side blanking time has expired until V_{REF} reaches the final value. See the *Power-Up and Power-Down Behavior* section for more details on power-up behavior.

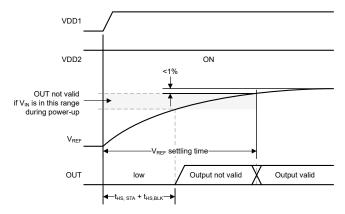


Figure 6-2. Output Behavior for Long Settling Times of the Reference Voltage

The reference pin can be driven by an external voltage source to change the comparator threshold during operation. However, do not drive V_{REF} dynamically across the V_{MSEL} threshold during normal operation because doing so changes the hysteresis of the comparator and can lead to unintentional switching of the output.

Figure 6-3 shows a mode selection timing diagram.

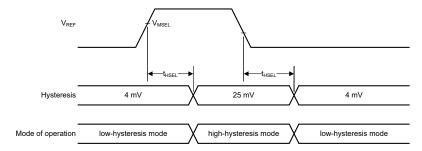


Figure 6-3. Mode Selection

6.3.3 Isolation Channel Signal Transmission

The AMC23C11 uses an on-off keying (OOK) modulation scheme, as shown in Figure 6-4, to transmit the comparator output states across the SiO_2 -based isolation barrier. The transmit driver (TX) shown in the *Functional Block Diagram* transmits an internally-generated, high-frequency carrier across the isolation barrier to represent a digital *one* and does not send a signal to represent a digital *zero*.

The receiver (RX) on the other side of the isolation barrier recovers and demodulates the signal and provides the data for the logic that drives the open-drain output buffer. The AMC23C11 transmission channel is optimized to achieve the highest level of common-mode transient immunity (CMTI) and the lowest level of radiated emissions caused by the high-frequency carrier and RX/TX buffer switching.

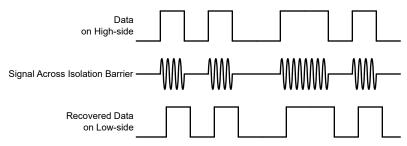


Figure 6-4. OOK-Based Modulation Scheme

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6.3.4 Open-Drain Digital Output

The AMC23C11 provides an open-drain output with an optional latching function. The output is actively pulled low when V_{IN} exceeds the threshold value defined by the voltage on the REF pin, see Figure 6-1.

The open-drain output is diode-connected to the VDD2 supply (see the *Functional Block Diagram*), meaning that the output cannot be pulled more than 500mV above the VDD2 supply before significant current begins to flow into the OUT pin. In particular, the open-drain output is clamped to one diode voltage above ground if VDD2 is at the GND2 level. This behavior is indicated by the gray shadings in Figure 6-5 through Figure 6-10.

On a system level, the CMTI performance of an open-drain signal line depends on the value of the pullup resistor. During a common-mode transient event with a high slew rate (high dV/dt), the open-drain signal line can be pulled low because of parasitic capacitive coupling between the high side and the low side of the printed circuit board (PCB). The effect of the parasitic coupling on the signal level is a function of the pullup strength and a lower value pullup resistor results in better CMTI performance. The AMC23C11 is characterized by a relatively weak pullup resistor value of $10k\Omega$ to make sure that the specified CMTI performance is met in a typical application with a $4.7k\Omega$ or lower pullup resistor.

6.3.4.1 Transparent Output Mode

The device is set to transparent mode when the LATCH pin is pulled low, thus allowing the output state to change and follow the input signal with respect to the programmed trip threshold. For example, when the input signal rises above the trip threshold, the OUT pin is pulled low. When the input signal drops below the trip threshold, the output returns to the default high output state. A common implementation using the device in transparent mode is to connect the OUT pin to a hardware interrupt input on a controller. As soon as an out-of-range condition is detected by the device and the OUT pin is pulled low, the controller interrupt terminal detects the output state change and can begin making changes to the system operation needed to address the out-of-range condition.

6.3.4.2 Latch Output Mode

Some applications do not have the functionality available to continuously monitor the state of the OUT pin to detect an overcurrent condition. A typical example of this application is a system that is only able to poll the OUT terminal state periodically to determine if the system is functioning correctly. If the device is set to transparent mode in this type of application, a change in the state of the OUT pin can be missed if the out-of-range condition does not appear during one of these periodic polling events.

Latch mode is specifically intended to accommodate these applications. The device is placed in latch mode by setting the voltage on the LATCH terminal to a logic high level. The difference between latch mode and transparent mode is how the output responds when an out-of-range event ends. In transparent mode, when the input signal drops below the trip threshold, the output state returns to the default high setting to indicate that the out-of-range event has ended.

In latch mode, when an out-of-range condition is detected and the OUT pin is pulled low, the OUT pin does not return to the default high level when the input signal drops below the trip threshold level. To clear the event, the LATCH terminal must be pulled low for at least 4 μ s. Pulling the LATCH pin low allows the OUT pin to return to the default high level, provided that the input signal has dropped below the trip threshold. If the input signal is still above the threshold when the LATCH pin is pulled low, the OUT terminal remains low. When the out-of-range event is detected by the system controller, the LATCH pin can be set back to high to place the device back into latch mode.

6.3.5 Power-Up and Power-Down Behavior

The open-drain output powers up in a high-impedance (Hi-Z) state when the low-side supply (VDD2) turns on. After power-up, if the high-side is not functional yet, the output is actively pulled low. As shown in Figure 6-5, this condition happens after the low-side start-up time plus the high-side fault detection delay time (t_{ISSTA} + t_{HSFIT}). Similarly, if the high-side supply drops below the undervoltage threshold (VDD1_{UV}), as described in Figure 6-8, for more than the high-side fault detection delay time during normal operation, the open-drain output is pulled low. This delay allows the system to shut down reliably when the high-side supply is missing.

Communication start between the high-side and low-side of the comparator is delayed by the high-side blanking time (t_{HS RI K}, a time constant implemented on the high-voltage side) to allow the voltage on the REF pin to settle, and to avoid unintentional switching of the comparator output during power-up.

Figure 6-5 through Figure 6-10 depict typical power-up and power-down scenarios.

In Figure 6-5, the low-side supply (VDD2) turns on but the high-side supply (VDD1) remains off. The output powers up in a Hi-Z state. After tHS. FLT, OUT is pulled low indicating a no-power fault on the high side.

In Figure 6-6, the high-side supply (VDD1) turns on long after the low-side supply (VDD2) turns on. The output is initially in an active-low state, see Figure 6-5. After the high-side supply is enabled, there is a duration of t_{HS, STA} + t_{HS, BLK} before the device assumes normal operation and the output reflects the current state of the comparator.

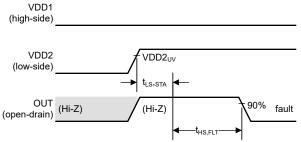


Figure 6-5. VDD2 Turns On, VDD1 Stays Off

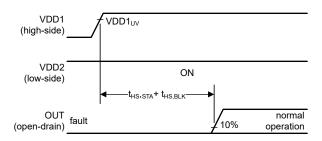
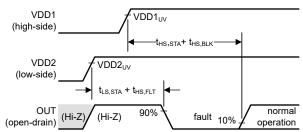


Figure 6-6. VDD2 is On; VDD1 Turns On (Long Delay)

In Figure 6-7, the low-side supply (VDD2) turns on, followed by the high-side supply (VDD1) with only a short delay. The output is initially in a Hi-Z state. The high-side fault detection delay (tHS.FLT) is shorter than the high-side blanking time (t_{HS.BLK}), and therefore the output is pulled low after t_{HS.FLT}, indicating that the high-side is not operational yet. After the high-side blanking time (t_{HS,BLK}) elapses, the device assumes normal operation and the output reflects the current state of the comparator.

In Figure 6-8, the high-side supply (VDD1) turns off, followed by the low-side supply (VDD2). After the high-side fault detection delay time (t_{HS,FLT}), the output is actively pulled low. As soon as VDD2 drops below the VDD2_{LIV} threshold, the output enters a Hi-Z state.

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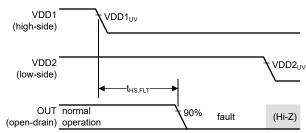


Figure 6-7. VDD2 Turns On, Followed by VDD1 (Short Delay)

Figure 6-8. VDD1 Turns Off, Followed by VDD2

In Figure 6-9, the low-side supply (VDD2) turns on after the high-side is fully powered up (the delay between VDD1 and VDD2 is greater than $(t_{HS,STA} + t_{HS,BLK})$). After the low-side start-up time $(t_{LS,STA})$, the device enters normal operation.

In Figure 6-10, the low-side supply (VDD2) turns off, followed by the high-side supply (VDD1). As soon as VDD2 drops below the VDD2 $_{UV}$ threshold, the output enters a Hi-Z state.

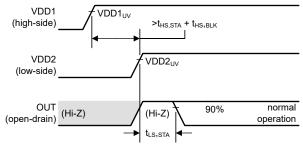


Figure 6-9. VDD1 Turns On, Followed by VDD2 (Long Delay)

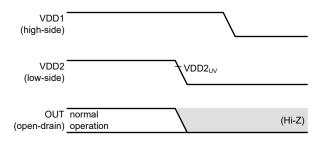


Figure 6-10. VDD2 Turns Off, Followed by VDD1

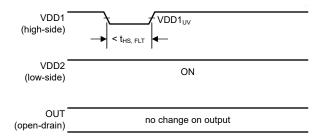
6.3.6 VDD1 Brownout and Power-Loss Behavior

Brownout is a condition where the VDD1 supply drops below the specified operating voltage range but the device remains functional. Power loss is a condition where the VDD1 supply drops below a level where the device stops being functional. Depending on the duration and the voltage level, a brownout condition can or can not be noticeable at the output of the device. A power-loss condition is always signaled on the output of the isolated comparator.

Figure 6-11 through Figure 6-13 show typical brownout and power-loss scenarios.

In Figure 6-11, VDD1 droops below the undervoltage detection threshold (VDD1 $_{UV}$) but recovers before the high-side-fault detection delay time ($t_{HS,FLT}$) expires. The brownout event has no effect on the comparator output.

In Figure 6-12, VDD1 droops below the undervoltage detection threshold (VDD1 $_{UV}$) for more than the high-side-fault detection delay time ($t_{HS,FLT}$). The brownout condition is detected as a fault and the output is pulled low after a delay equal to $t_{HS,FLT}$. The device resumes normal operation as soon as VDD1 recovers above the VDD1 $_{UV}$ threshold.



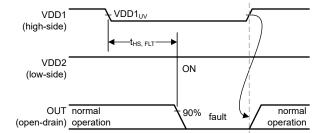


Figure 6-11. Output Response to a Short Brownout Event on VDD1

Figure 6-12. Output Response to a Long Brownout Event on VDD1

In Figure 6-13, VDD1 droops below the power-on-reset (POR) threshold (VDD1_{POR}). The power-loss condition is detected as a fault and the output is pulled low after a delay equal to $t_{HS,FLT}$. The device resumes normal operation after a delay equal to $t_{HS,STA} + t_{HS,BLK}$ after VDD1 recovers above the VDD1_{UV} threshold.

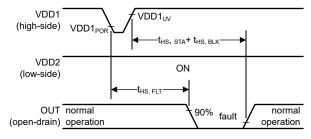


Figure 6-13. Output Response to a Power-Loss Event on VDD1

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6.4 Device Functional Modes

The AMC23C11 is operational when the power supplies VDD1 and VDD2 are applied, as specified in the *Recommended Operating Conditions* table.

The voltage on the REF pin affects the threshold of the comparator. For reference voltages below the V_{MSEL} threshold, the comparator operates in low-hysteresis mode. For reference voltages above the V_{MSEL} threshold, the comparator operates in high-hysteresis mode as described in the *Reference Input* section.

The device has two output operating modes that are selected based on the LATCH input pin setting: transparent mode and latch mode. These modes affect how the OUT pin responds to the changing input signal conditions. See the *Open-Drain Digital Output* section for details.

7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

7.1 Application Information

With low response time, high common-mode transient immunity (CMTI), and a reinforced isolation barrier, the AMC23C11 is designed to provide fast and reliable overcurrent and overvoltage detection for high-voltage applications in harsh and noisy environments.

7.2 Typical Application

7.2.1 DC Link Overcurrent Detection

DC link overcurrent detection is a common requirement in DC/DC converter and motor-drive designs. Although the inductor current of a DC/DC converter or the phase currents of a motor drive are typically sensed for control purposes, phase current monitoring alone is not sufficient to detect all possible overcurrent conditions (such as shoot-through in the power stage, or DC+ and DC- shorts to ground). The most comprehensive way of implementing DC link overcurrent detection is to monitor the current in the DC+ and DC- lines. This detection, as illustrated in Figure 7-1, can be achieved by monitoring the voltage drop across two shunt resistors.

The DC+ load current flowing through the shunt resistor R10 produces a positive voltage with respect to GND1 that is monitored by the AMC23C11. When the voltage drop across R10 exceeds the reference value set by the external resistor R11, the comparator trips and signals the overcurrent event on the open-drain output OUT.

The DC- load current flowing through the shunt resistor R20 produces a negative voltage in respect to GND1 that is monitored by a AMC23C12. When the voltage drop across R20 exceeds the reference value set by the external resistor R21, the comparator trips and signals the overcurrent event on the open-drain output OUT.

The open-drain outputs from both isolated comparators are shorted together to form a single alert signal to the microcontroller unit (MCU). Similarly, both LATCH signals are tied together and can be controlled by a single GPIO pin from the MCU.

The isolated comparator on the DC+ side requires a high-side power supply that is referenced to the DC+ potential. A low-cost solution is based on the push-pull driver SN6501 and a transformer that supports the desired isolation voltage ratings. The integrated low-dropout (LDO) regulator on the high-side of the AMC23C11 allows direct connection of the VDD1 pin to the transformer output and no further preregulation of the transformer output voltage is required.

The isolated comparator on the DC- side requires a high-side power supply that is referenced to the DC- potential. A common solution is to power the isolated comparator from the low-side gate driver supply, as illustrated in Figure 7-1, or any other voltage supply referenced to DC-. The integrated low-dropout (LDO)

regulator on the high side of the AMC23C12 supports a wide range of input voltages and greatly simplifies the power-supply design.

The fast response time and high common-mode transient immunity (CMTI) of the AMC23C11 provide reliable and accurate operation even in high-noise environments.

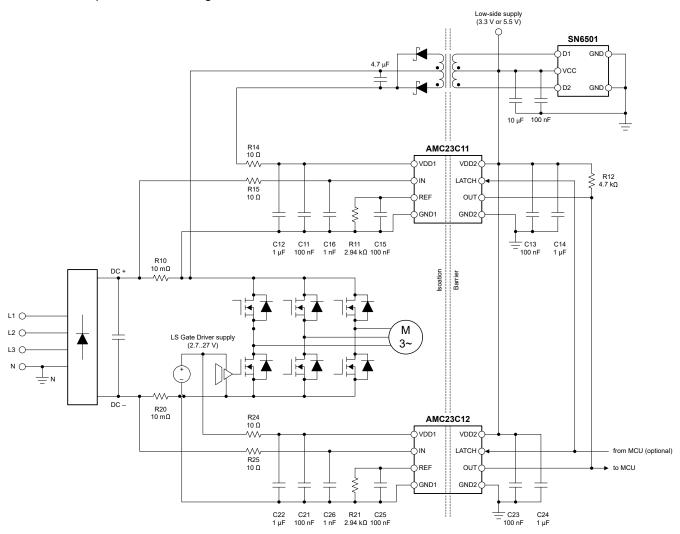


Figure 7-1. Using the AMC23C11 for DC+ Overcurrent Detection

7.2.1.1 Design Requirements

Table 7-1 lists the parameters for the application example in Figure 7-1.

Table 7-1. Design Requirements

PARAMETER	VALUE
High-side supply voltage	3V to 27V
Low-side supply voltage	2.7V to 5.5V
Shunt-resistor value	10mΩ
Overcurrent detection threshold	30A

Product Folder Links: AMC23C11

7.2.1.2 Detailed Design Procedure

The value of the shunt resistors (R10 and R20) in this example is $10m\Omega$. At the desired 30A overcurrent detection level, the voltage drop across the shunt resistor is $10m\Omega \times 30A = 300mV$. The positive-going trip threshold of the comparator is $V_{REF} + V_{HYS}$, where V_{HYS} is 4mV (as specified in the *Electrical Characteristics* table) and V_{REF} is the voltage across R11 (R12, respectively) that is connected between the REF and GND1 pins. R11 and R12 are calculated as $(V_{TRIP} - V_{HYS}) / I_{REF} = (300mV - 4mV) / 100\mu A = 2.96k\Omega$. The next lower value from the E96 series (1% accuracy) is $2.94k\Omega$, resulting in an overcurrent trip threshold (rising) of 29.8A.

A 10Ω , 1nF RC filter (R15, C16 and R25, C26, respectively) is placed at the input of the comparator to filter the input signal and reduce noise sensitivity. This filter adds $10\Omega \times 1$ nF = 10ns of propagation delay that must be considered when calculating the overall response time of the protection circuit. Larger filter constants are preferable to increase noise immunity if the system can tolerate the additional delay.

Table 7-2 summarizes the key parameters of the design.

Table 7-2. Overcurrent Detection Design Example

PARAMETER	VALUE
Reference resistor value (R11, R21)	2.94kΩ
Reference capacitor value (C15, C25)	100nF
Reference voltage	296mV
Reference voltage settling time (to 90% of final value)	690µs
Overcurrent trip threshold (rising)	298mV / 29.8A
Overcurrent trip threshold (falling)	294mV / 29.4A

7.3 Application Curves

Figure 7-2 shows the typical response of the AMC23C11 to a triangular input waveform with an amplitude of 310mV_{PP} . The output (OUT) switches when VIN crosses the 250mV level determined by the REF pin voltage that is biased to 250mV in this example.

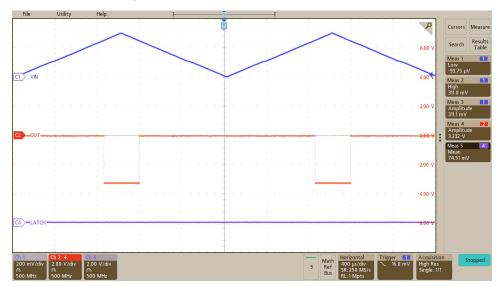


Figure 7-2. Output Response of the AMC23C11 to a Triangular Input Waveform

The integrated LDO of the AMC23C11 greatly relaxes the power-supply requirements on the high-voltage side and allows powering the device from non-regulated transformer, charge pump, and bootstrap supplies. As given by the following image, the internal LDO provides a stable operating voltage to the internal circuitry, allowing the trip thresholds to remain mostly undisturbed even at ripple voltages of 2V_{PP} and higher.

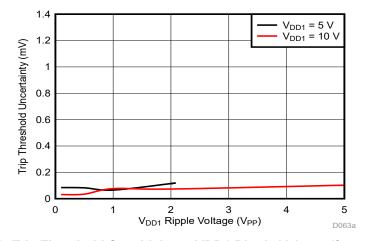


Figure 7-3. Trip Threshold Sensitivity to VDD1 Ripple Voltage ($f_{RIPPLE} = 10kHz$)

Product Folder Links: AMC23C11



7.4 Best Design Practices

Keep the connection between the low-side of the sense resistor and the GND1 pin of the AMC23C11 short and low impedance. Any voltage drop in the ground line adds error to the voltage sensed at the input of the comparator and leads to inaccuracies in the trip thresholds.

For best common-mode transient immunity, place the filter capacitor C5 as closely to the REF pin as possible as illustrated in Figure 7-5. Use a low-value pullup resistor ($<10k\Omega$) on the open-drain output, as explained in the *Open-Drain Digital Output* section, to minimize the effect of capacitive coupling on the open-drain signal line during a common-mode transient event.

Do not operate the device with the REF pin biased close to the V_{MSEL} threshold (450mV to 600mV range) to avoid dynamic switching of the comparator hysteresis as explained in the *Reference Input* section.

The AMC23C11 provides a limited 200 μ s blanking time ($t_{HS,BLK}$) to allow the reference voltage (V_{REF}) to settle during start-up. For many applications, the reference voltage takes longer to settle than the 200 μ s blanking time and the output of the comparator can possibly glitch during system start-up as described in Figure 6-2. Consider the reference voltage settling time in the overall system start-up design.

7.5 Power Supply Recommendations

The AMC23C11 does not require any specific power-up sequencing. The high-side power supply (VDD1) is decoupled with a low-ESR, 100nF capacitor (C1) parallel to a low-ESR, 1µF capacitor (C2). The low-side power supply (VDD2) is equally decoupled with a low-ESR, 100nF capacitor (C3) parallel to a low-ESR, 1µF capacitor (C4). Place all four capacitors (C1, C2, C3, and C4) as close to the device as possible. Figure 7-4 shows a decoupling schematic for the AMC23C11.

For high VDD1 supply voltages (>5.5V) place a 10Ω resistor (R4) in series with the VDD1 power supply for additional filtering.

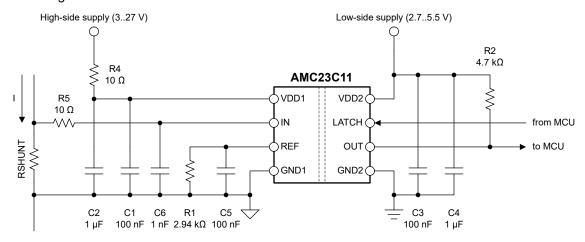


Figure 7-4. Decoupling of the AMC23C11

Capacitors must provide adequate effective capacitance under the applicable DC bias conditions experienced in the application. Multilayer ceramic capacitors (MLCCs) typically exhibit only a fraction of the nominal capacitance under real-world conditions and this factor must be taken into consideration when selecting these capacitors. This problem is especially acute in low-profile capacitors, in which the dielectric field strength is higher than in taller components. Reputable capacitor manufacturers provide capacitance versus DC bias curves that greatly simplify component selection.

7.6 Layout

7.6.1 Layout Guidelines

Figure 7-5 shows a layout recommendation with the critical placement of the decoupling capacitors (as close as possible to the AMC23C11 supply pins) and placement of the other components required by the device.

7.6.2 Layout Example

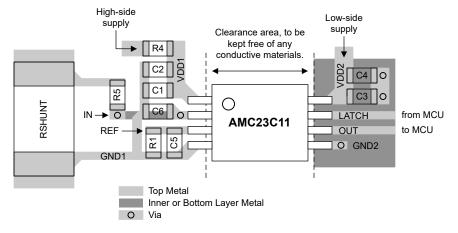


Figure 7-5. Recommended Layout of the AMC23C11

Product Folder Links: AMC23C11

8 Device and Documentation Support

8.1 Documentation Support

8.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Isolation Glossary application note
- Texas Instruments, Semiconductor and IC Package Thermal Metrics application note
- Texas Instruments, ISO72x Digital Isolator Magnetic-Field Immunity application note
- Texas Instrument, SN6501 Transformer Driver for Isolated Power Supplies data sheet
- Texas Instruments, Isolated Amplifier Voltage Sensing Excel Calculator design tool

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.



CI	hanges from Revision * (February 2022) to Revision A (July 2022)	Page
•	Changed document status from advance information to production data	1

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: AMC23C11

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
AMC23C11DWV	Active	Production	SOIC (DWV) 8	64 TUBE	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	MC23C11
AMC23C11DWV.A	Active	Production	SOIC (DWV) 8	64 TUBE	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	MC23C11
AMC23C11DWV.B	Active	Production	SOIC (DWV) 8	64 TUBE	-	Call TI	Call TI	-40 to 125	
AMC23C11DWVR	Active	Production	SOIC (DWV) 8	1000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	MC23C11
AMC23C11DWVR.A	Active	Production	SOIC (DWV) 8	1000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	MC23C11
AMC23C11DWVR.B	Active	Production	SOIC (DWV) 8	1000 LARGE T&R	-	Call TI	Call TI	-40 to 125	

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

www.ti.com 8-Nov-2025

PACKAGE MATERIALS INFORMATION

www.ti.com 18-Jul-2025

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ĺ	AMC23C11DWVR	SOIC	DWV	8	1000	330.0	16.4	12.05	6.15	3.3	16.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 18-Jul-2025



*All dimensions are nominal

	Device	Package Type	kage Type Package Drawing		SPQ	Length (mm)	Width (mm)	Height (mm)	
ı	AMC23C11DWVR	SOIC	DWV	8	1000	350.0	350.0	43.0	

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
AMC23C11DWV	DWV	SOIC	8	64	505.46	13.94	4826	6.6
AMC23C11DWV.A	DWV	SOIC	8	64	505.46	13.94	4826	6.6



SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.



SOIC



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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